

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions and listings of claims in the application:

LISTING OF THE CLAIMS:

1. (Original) An error rate determining method for determining an error rate of a semiconductor memory device implementing detection and correction of an error existing in a plurality of pieces of data stored in said semiconductor memory device by using said pieces of data and inspection bits provided for said pieces of data, said error rate determining method comprising the steps of:

cumulatively adding a first value to a total in the event of a detected first detection signal indicating non-existence of an error in said pieces of data;

subtracting a second value greater than said first value from said total in the event of a detected second detection signal indicating existence of an error in said pieces of data;
and

determining said error rate on the basis of a value of said total.

2. (Original) An error rate determining method according to claim 1, whereby said pieces of data and said inspection bits are read out from a memory circuit.

Claims 3-13 (Cancelled)